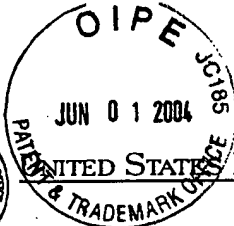


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APPL NO.	FILING OR 371 (c) DATE	ART UNIT	FIL FEE REC'D	ATTY. DOCKET NO	DRAWINGS	TOT CLMS	IND CLMS
10/779,905	02/17/2004	2133	770	02008.071002	38	3	3

CONFIRMATION NO. 9605

22511
 OSHA & MAY L.L.P.
 1221 MCKINNEY STREET
 HOUSTON, TX 77010

FILING RECEIPT



OC000000012596942

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Applicant(s)

Masahiro Ishida, Tokyo, JAPAN;
 Takahiro Yamaguchi, Tokyo, JAPAN;
 Yoshihiro Hashimoto, Tokyo, JAPAN;

Domestic Priority data as claimed by applicant

This application is a DIV of 09/980,891 12/03/2001
 which is a 371 of PCT/JP01/02910 04/04/2001

Foreign Applications

04
 JAPAN 2000-101867 04/06/2000

If Required, Foreign Filing License Granted: 05/11/2004

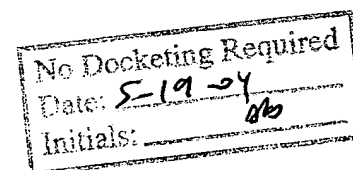
Projected Publication Date: 08/19/2004

Non-Publication Request: No

Early Publication Request: No

Title

Method and apparatus for defect analysis of semiconductor integrated circuit



Preliminary Class

714

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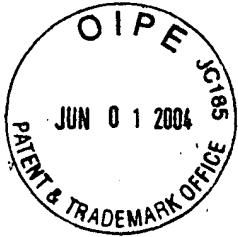
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PATENT
ATTORNEY DOCKET NO. 02008/071002
U.S. PATENT APPLICATION NO. 10/799,905

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Masahiro ISHIDA, *et al.* Art Unit : 2133
Serial No. : 10/779,905 Examiner :
Filed : February 17, 2004
Title : METHOD AND APPARATUS FOR DEFECT ANALYSIS OF
SEMICONDUCTOR INTEGRATED CIRCUIT

Commissioner of Patents
P.O. Box 1450
Alexandria, VA 22313-1450

REQUEST TO CORRECT FILING RECEIPT

Applicants request that the filing date of the Japanese priority document be corrected from "04/06/2000" to --04/04/2000--.

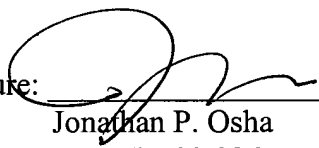
Enclosed is a copy of the filing receipt as received from the PTO. The correct foreign priority information should be --Japanese Application No. 2000-101867, 04/04/2000--, as shown in the enclosed copy of the signed Declaration and Power of Attorney filed with this Divisional Patent Application on February 17, 2004.

Because this is a PTO error, no petition is believed necessary. However, if a petition is deemed to be required, please consider this paper as such and charge the appropriate fees to the Deposit Account 50-0591, reference No. 02008/071002.

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Account and reference No. 02008/071002.

Date: 5/27/04

Signature: _____


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Facsimile: 713/228-8778

CERTIFICATE OF MAILING BY FIRST CLASS MAIL (37 CFR 1.8)

Applicant(s): Masahiro ISHIDA, et al.

Docket No.

02008/071002

Serial No.

10/779,905

Filing Date

February 17, 2004

Examiner

Group Art Unit

2133

Invention: **METHOD AND APPARATUS FOR DEFECT ANALYSIS OF SEMICONDUCTOR INTEGRATED CIRCUIT**

JUN 01 2004

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